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Auftraggeber: Client:	<b>Schneider Electric India</b> Beary's Global Research Ashram Road Bidarahalli I	Friangle sy.No 63/3B,	, Gorvigere Village, Whitefield 067, India.
Gegenstand der Prüfung: Test item:	Uninterruptible Power Supply	Zustand der Anlag Eingang: Condition of Equipri	Good
Bezeichnung: Identification:	2G online UPS - SRT1500RMXLA-NC	Serien-Nr.: Serial No.:	AS1632190456
Wareneingangs-Nr.: Receipt No.:	1803173634	Eingangsdatum: Date of receipt:	27-Oct-2016
<b>Prüfort:</b> Testing location:	TÜV Rheinland (India) Pvt. Ltd., Plot No.: 108, West Wing, Electronics City Phase 1, Bangalore - 560100		
<b>Prüfgrundlage:</b> Test specification:	IEC 61000-4-5:2014 (AC	6000MHz, level 3 (10) power ports: level 3 (: power ports: level 3 (: power ports: level 3 (	V/m)) ±2kV),signal ports: level 4 (±2kV)) ±2kV) signal ports: level 2 (±1kV)) 10V), signal ports: level 3 (10V))
<b>Prüfergebnis:</b> Test Result:	<b>Der Prüfgegenstand ents</b> The test item passed the t		iter Prüfgrundlage(n).
Prüflaboratorium: Testing Laboratory:	<b>TÜV Rheinland (India) Pv</b> Plot No.: 108, West Wing,		se 1, Bangalore - 560100
geprüft/ tested by:		kontrolliert/ reviewe	ed by:
02-Dec-2016 Raghuna Engineer Datum Name/Stel Date Name/Pos	lung Unterschrift	02-Dec-2016 M Abdu Manag Datum Name/S Date Name/F	ger Unterschrift
Sonstiges/ Other Aspec	ts: Not Applicable		ie
F(ail) = N/A =	entspricht Prüfgrundlage entspricht nicht Prüfgrundlage nicht anwendbar nicht getestet	Abbreviations: P(a F(a N// N/1	4 = not applicable
	by the National Accreditation B herein have been performed in		alibration Laboratories, INDIA. The tests
auszugsweise verviel This test report relates to the	fältigt werden. Dieser Bericht	berechtigt nicht zur V mission of the test cent	Genehmigung der Prüfstelle nicht /erwendung eines Prüfzeichens. tre this test report is not permitted to be
		deleterate the transferred state and the	info-ind@ind.tuv.com · Web: www.tuv.com

TÜV Rheinland (India) Pvt. Ltd. · Tel.: +91 80 30554319 · Fax: +91 80 30554342 · Mail: info-ind@ind.tuv.com · Web: www.tuv.com Annex 5/ QMA 30.036.02 IND/Rev.:2011.12.21

CIN: U72501KA1996PTC020653



TEST SUMMARY         State of the second	
SUSCEPTIBILITY) RESULT: PASS 5.1.2 CONDUCTED DISTURBANCES INDUCED BY RADIO-FREQUENCY FIELDS (C SUSCEPTIBILITY) RESULT: PASS 5.1.3 CONDUCTED IMMUNITY TO LOW FREQUENCY FIELDS RESULT: PASS 5.1.4 POWER FREQUENCY MAGNETIC FIELDS RESULT: PASS 5.2.1 ELECTRICAL FAST TRANSIENTS AND BURSTS RESULT: PASS 5.2.2 SURGES	
Susceptibility)         RESULT:       PASS         5.1.3       Conducted Immunity to Low FREQUENCY Fields         RESULT:       PASS         5.1.4       Power Frequency Magnetic Fields         RESULT:       PASS         5.2.1       Electrical Fast Transients and Bursts         RESULT:       PASS         5.2.2       Surges	
RESULT:       PASS         5.1.4       POWER FREQUENCY MAGNETIC FIELDS RESULT:         FASS         5.2.1       ELECTRICAL FAST TRANSIENTS AND BURSTS RESULT:         FASS         5.2.2       SURGES	
RESULT: PASS 5.2.1 ELECTRICAL FAST TRANSIENTS AND BURSTS RESULT: PASS 5.2.2 SURGES	
RESULT: PASS 5.2.2 SURGES	
5.2.3 ELECTROSTATIC DISCHARGES RESULT: PASS	
5.3.1 Voltage Dips RESULT: Pass	
5.3.2 VOLTAGE INTERRUPTIONS RESULT: PASS	



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### 1. General Remarks

According to the product specification testing levels & performance criteria were considered according to 62040-2.

### Interface cable in EUT

Interfaces	Max. cable length	Cable Type (Shielded/Un shielded)
Serial Cable	4.5m	Unshielded
USB 1(On Unit)	5m	Shielded
USB 2(On NMC)	5m	Shielded
USB 3(On NMC)	5m	Shielded
Universal I/O 1(On NMC)	4m	Unshielded
Universal I/O 2(On NMC)	4m	Unshielded
Network 1(On Unit)	15m	Unshielded
Network 2(On NMC)	15m	Unshielded
EPO(On Unit)	5m	Unshielded

EUT does not support any other cable apart from the cables mentioned in the above table.

UPS models listed below are identical to each other mechanically and electrically. The only differences between these models are the installation practices and the addition of network management card. Please find below the differences between the models. External battery packs SRT48RMBP and SRT48BP are accessories to the UPS and are identical to each other

Product SKU	Product Description
SRT1500XLA	APC Smart-UPS SRT 1500VA 120V
SRT1500RMXLA	APC Smart-UPS SRT 1500VA RM 120V
SRT1500RMXLA-NC	APC Smart-UPS SRT 1500VA RM 120V Network Card
SRT1000XLA	APC Smart-UPS SRT 1000VA 120V
SRT1000RMXLA	APC Smart-UPS SRT 1000VA RM 120V
SRT1000RMXLA-NC	APC Smart-UPS SRT 1000VA RM 120V Network Card
SRT48RMBP	APC Smart-UPS SRT 48V 1.5 kVA and 1 kVA RM Battery Pack
SRT48BP	APC Smart-UPS SRT 48V 1.5 kVA and 1 kVA Battery Pack

### **1.1 Complementary Materials**

No attachments along this test report.



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#### 2. **Test Sites**

### 2.1 Test Facilities

1) TÜV Rheinland (India) Pvt. Ltd. Plot No. 108, West Wing, **Electronic City Phase 1** Hosur Road Bangalore – 560 100. Website: www.tuv.com

This test site is in accordance with CISPR 16 for measurement of radio interference.

The used test equipment is in accordance with CISPR 16 for measurement of radio interference. The tests have been conducted by a TÜV Rheinland testing engineer.

#### 2.2 List of Test and Measurement Instruments

Kind of Equipment	Manufacturer	Model Name	Serial Number	Calibrated until	
For Radiated Susceptib	ility (RS)			•	
Signal Generator	Agilent	E8257D-ATO-1895	MY51110514	10-Jan-2018	
RF Power Amplifier	MILMEGA	80RF1000-500	1045085	NA	
RF Power Amplifier	MILMEGA	AS0102-200	1045089	NA	
RF Power Amplifier	MILMEGA	AS1860-100	1045088	NA	
Stacked Double Logged Periodic Antenna	Schwarzbeck	STLP9128D	9128D037	NA	
Power Meter	Agilent	N1914A	MY50001234	02-Feb-2018	
For Conducted Susceptibility (CS)					
Conducted Immunity Test System	EM Test	CWS 500D	V0732102786	29-Feb-2017	
Attenuator	EM Test	ATT6/75	1009-19	26-Feb-2017	
EM Clamp	EM Test	EM 101	35861	26-Feb-2017	
CDN	EM Test	M5	0310-01	25-Feb-2017	
Signal Line CDN	EM Test	CDN-T8-RJ45	1007-67	29-Feb-2017	
For Low Frequency Cor	ducted Disturba	ince			
Arbitrary Waveform Generator	Agilent	33220A	MY44053559	07-Nov-2017	
Audio Isolation transformer	Solar Electronics	6220-1A	-	NA	

**Table 1: List of Test and Measurement Equipment** 



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Kind of Equipment	Manufacturer	Model Name	Serial Number	Calibrated until	
For Electrical Fast Tran	nsients (EFT) & Su	ırge		<u> </u>	
EMC Immunity Test System	EMC Partner	TRA3000	1515	13-Jul-2017	
Capacitive Coupling Clamp	EMC Partner	CN-EFT1000	679	22-Jul-2017	
Telecom Line CDN	ThermoElectron	CM-TELCD	0603297	NA	
For Electrostatic Discharges (ESD)					
ESD Simulator	Noiseken	ESS 2002 EX	ESS0999547	20-Sep-2017	
For Power Frequency Magnetic Field					
Magnetic Field immunity Loop	FCC	F-1000-4-8/9/10-L- 1M	05013	05-Nov-2017	
Earth Bond Tester	Lumetronics	EC-12	150903	21-Nov-2016	
For Voltage Dips & Interruptions					
EMC Tester	EMC Partner	TRA3000	1515	13-Jul-2017	

### 3. General Product Information

### 3.1 Product Function and Intended Use

The EUT is a Uniterruptible Power Supply which provides reliable power to connected load and when there is power failure.

### 3.2 Ratings and System Details

System Input Voltage:	AC 120V
Frequency:	60Hz
Input Current:	Max 16A
Protection Class:	I

### 3.3 Noise Generating and Noise Suppressing Parts

Noise generating & suppressing parts are integral part of the design

### 3.4 Submitted Documents

1. User Manual



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4. Test Set-up and Operation Modes

### 4.1 **Principle of Configuration Selection**

**Immunity:** The equipment under test (EUT) was configured to have its highest possible susceptibility against the tested phenomena. The test modes were adapted accordingly in reference to the instructions for use.

### 4.2 Operation Modes

The operation modes used for testing are:

A. EUT to be operated in Normal Operation @ 120V 60Hz Online Mode

### 4.3 Physical Configuration for Testing

For more details, refer to section: Photographs of the Test Set-Up.

### 4.4 Test Operation & Test Software

During testing in Online mode, EUT was powered with an input voltage of 120 VAC/60Hz. EUT was loaded with a bulb and resistive load of 1350W.

Application software: Microlink simulator Software version: ulSim 4.0.0.6 Firmware version: UPSa5.1

### 4.5 Special Accessories and Auxiliary Equipment

Item	Manufacturer	Туре
PC	DELL	-
Power Supply	Chroma	-
Load	Avtron	-

### 4.6 Countermeasures to achieve EMC Compliance

No additional measures were employed to achieve compliance.



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5. Test Results	IMMUNITY		
5.1 Continuous Di	sturbances		
5.1.1 Radiated Radio-frequency Electromagnetic Fields (Radiated Susceptibility)			
RESULT:		Pass	
Date of testing:	27-Oct-2016		
Ambient temperature: Relative humidity: Atmospheric pressure:	25°C 59% 91kPa		
Test procedure:	IEC 61000-4-3:	2010	
Frequency range: Test level: Modulation: Step size: Dwell time: Supply voltage during testin Test mode applied:	80-6000MHz 3 (10V/m) (unm 80% AM, 1kHz 1% 2.85s AC 120V A	odulated, rms.)	
Performance criterion:	А		
Met criterion:	А		

#### Note:

The EUT was placed on a non-conductive table 80cm above the floor in an anechoic chamber. Each face of the EUT and the attached cables were exposed in sequence to the electromagnetic field produced by a transmitting antenna. For each EUT orientation, the frequency was swept from 80MHz to 6GHz. The EUT operation was monitored during the test. It was verified that its response to the external disturbance remains within the performance specifications.



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Table 2: Immunity against Radiated Radio-frequency Electromagnetic Fields

Field Polarization	Side of EUT	Frequency	Result	Remark
Vertical	Front	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Vertical	Rear	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Vertical	Left	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Vertical	Right	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Horizontal	Front	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Horizontal	Rear	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Horizontal	Left	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.
Horizontal	Right	80-6000 MHz	Pass	EUT operated as intended, no degradation of function.



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5.1.2 Conducted Disturbances induced by Radio-frequency Fields (Conducted Susceptibility)				
RESULT:		Pass		
Date of testing:	07-Nov-2016	6		
Ambient temperature: Relative humidity: Atmospheric pressure:	24°C 56% 91kPa			
Test procedure:	IEC 61000-4	I-6:2013		
Severity level: Source impedance: Frequency range: Modulation: Sweep mode: Step size: Dwell time: Supply voltage during test Test mode applied:	3 (10V) for s 150Ω 150kHz - 80 80% AM, 1k Automatic 1% 2.85s			
Performance criterion:	А			
Met criterion:	А			

#### Note:

The EUT and its associated accessories were placed on a non-conductive support 10cm above a reference ground plane. Radio-frequency conducted disturbances were injected into the EUT cables via a CDN or a coupling clamp. For each cable selected for testing, the frequency was swept from 150kHz to 80MHz. The EUT operation was monitored during the test. It was verified that its response to the external disturbance remains within the performance specifications.



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Table 3: Immunity against Conducted Disturbances induced by Radio-frequency Fields

Coupling Port	Coupling Method:	Result	Remark
AC Input: Line (L), Neutral(N),PE	CDN M-5	Pass	EUT operated as intended, no degradation of function.
Output Power: Line (L), Neutral(N),PE	CDN M-5	Pass	EUT operated as intended, no degradation of function.
EPO Cable	EM Clamp	Pass	EUT operated as intended, no degradation of function.
Serial Cable	EM Clamp	Pass	EUT operated as intended, no degradation of function.
USB Cable	EM Clamp	Pass	EUT operated as intended, no degradation of function.
Universal I/O 1	EM Clamp	Pass	EUT operated as intended, no degradation of function.
Universal I/O 2	EM Clamp	Pass	EUT operated as intended, no degradation of function.
Ethernet (NMC) Cable	CDN-T8-RJ45	Pass	EUT operated as intended, no degradation of function.
Ethernet (Unit) Cable	CDN-T8-RJ45	Pass	EUT operated as intended, no degradation of function.



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5.1.3 Conducted Im	munity to low frequency Fi	ields
RESULT:		Pass
Date of testing:	21-Nov-2016	
Ambient temperature: Relative humidity: Atmospheric pressure:	25°C 57% 91kPa	
Test procedure:	IEC 61000-2-2	:2002
Severity level: Frequency range: Sweep mode: Step size: Dwell time: Supply voltage during tes Test mode applied:	140Hz - 360Hz Automatic 1% 3.00s	power ports (unmodulated, rms.)
Performance criterion:	А	
Met criterion:	А	

Note:

The EUT and its associated accessories were placed on a non-conductive support 10cm above a reference ground plane. Low-frequency conducted disturbances were injected into the EUT cables. For each cable selected for testing, the frequency was swept from 140Hz to 360Hz. The EUT operation was monitored during the test. It was verified that its response to the external disturbance remains within the performance specifications.

#### Table 4: Immunity against Conducted Disturbances induced by Low-frequency Fields

Coupling Port	Coupling Method:	Result	Remark
AC Input:	Series Injection	Pass	EUT operated as intended,
Line (L), (N), PE	Series injection	T A33	no degradation of function.



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5.1.4 Power Frequence	cy Magnetic Fields	
RESULT:		Pass
Date of testing:	10-Nov-2016	
Ambient temperature: Relative humidity: Atmospheric pressure: Test procedure: Severity level: Frequency: Supply voltage during testi Test mode applied:	24°C 54% 91kPa IEC 61000-4-8:2009 4 (30A/m) 60Hz AC 120V A	
Compliance criteria:	В	
Met criterion:	A	

#### Table 5: Immunity against Power Frequency Magnetic Field:

Field Polarization	Coil Orientation	Result	Remark
Horizontal	Parallel to front side.	Pass	EUT operated as intended, no degradation of function.
Horizontal	Perpendicular to front side.	Pass	EUT operated as intended, no degradation of function.
Vertical	Horizontal to front side.	Pass	EUT operated as intended, no degradation of function.



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5.2 Transient Dist	urbances	
5.2.1 Electrical Fast T	ransients and Bursts	
RESULT:		Pass
Date of testing:	08-Nov-2016	
Ambient temperature: Relative humidity: Atmospheric pressure:	26°C 55% 91kPa	
Test procedure:	IEC 61000-4-4:2012	
Severity level: Repetition rate: Test duration: Supply voltage during testin Test mode applied:	3 (±2kV) AC power p 4 (±2kV) signal ports 5kHz ≥60s AC 120V A	
Performance criterion:	В	
Met criterion:	А	

Note:

The EUT and its attached cables were placed on a non-conductive support 10cm above a reference ground plane. Electrical fast transients and bursts were injected into each cable selected for testing via a CDN. The EUT operation was monitored during the test.



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#### Table 6: Immunity against Electrical Fast Transients and Bursts:

Coupling Method: CDN Injection					
Coupling Port	Test Voltag	e / Result	Remark		
AC Input:	±500V	Pass	EUT operated as intended,		
L1 ( <b>L</b> ), L2 ( <b>N</b> )	±1000V	PASS	no degradation of function.		
PE (or reference ground)	±2000V	PASS	no degradation of function.		
AC Output:	±500V	PASS	FUT operated as intended		
L1 ( <b>L</b> ), L2 ( <b>N</b> )	±1000V	PASS	EUT operated as intended, no degradation of function.		
PE (or reference ground)	±2000V	Pass	no degradation of function.		

#### Table 7: Immunity against Electrical Fast Transients (EFT), on Signal Ports

Coupling Method: Capacitive Clamp					
Coupling Port	Test Voltag	e / Result	Remark		
EPO Cable	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		
Serial Cable	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		
USB Cable	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		
Universal I/O 1	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		
Universal I/O 2	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		
Ethernet (NMC) Cable	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		
Ethernet (Unit) Cable	±500V ±1000V ±2000V	Pass Pass Pass	EUT operated as intended, no degradation of function.		



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5.2.2 Surges		
RESULT:		Pass
Date of testing:	08-Nov-2016	
Ambient temperature: Relative humidity: Atmospheric pressure:	25°C 57% 91kPa	
Test procedure:	IEC 61000-4-5:20	14
Severity level: Source impedance: Test voltages: Coupling phases: Number of surges: Time between pulses: Supply voltage during test Test mode applied:	ting: $3 (\pm 2kV)$ for AC points $2 (\pm 1kV)$ for Signal $2\Omega, 12\Omega$ $\pm 500V, \pm 1000V, \pm$ $\pi/2, \pi, 3\pi/2$ (90°, 1 5 (for each paramediate AC 120V A	Il Ports 2000V 180°, 270°)
Performance criterion:	В	
Met criterion:	А	

#### Note:

The EUT and its attached cables were placed on a non-conductive support 80cm above a reference ground plane. Surges were injected into each cable selected for testing via a CDN. The EUT operation was monitored during the test.



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Table 8: Surge Immunity Tests, on AC Power port

Coupling Port	Test Voltage	Coupling Phase	Result	Remark
Input port				
Input Port: L1 (L) - L2 ( <b>N</b> ) Differential (Line to Neutral)	±500V ±1000V	π/2 π 3π/2	Pass	EUT operated as intended, no degradation of function.
Input Port: L1 ( <b>L</b> ) – <b>PE</b> Common (Line to Ground)	±500V ±1000V ±2000V	π/2 π 3π/2	Pass	EUT operated as intended, no degradation of function.
Input Port: L2 ( <b>N</b> ) - <b>PE</b> Common (Neutral to Ground)	±500V ±1000V ±2000V	π/2 π 3π/2	Pass	EUT operated as intended, no degradation of function.
Output port				
Output Port: L1 ( <b>L</b> ) - L2 ( <b>N</b> ) Differential (Line to Neutral)	±500V ±1000V	π/2 π 3π/2	Pass	EUT operated as intended, no degradation of function.
Output Port: L1 ( <b>L</b> ) – <b>PE</b> Common (Line to Ground)	±500V ±1000V ±2000V	π/2 π 3π/2	Pass	EUT operated as intended, no degradation of function.
Output Port: L2 ( <b>N</b> ) - <b>PE</b> Common (Neutral to Ground)	±500V ±1000V ±2000V	π/2 π 3π/2	Pass	EUT operated as intended, no degradation of function.

#### Table 9: Surge Immunity Tests, on Signal Port

Coupling Port	Coupling Mode	Test Voltage	Result	Remark
Ethernet (NMC) Cable	CM-TELCD	±500V ±1000V	Pass	EUT operated as intended, no degradation of function.
Ethernet (Unit) Cable	CM-TELCD	±500V ±1000V	Pass	EUT operated as intended, no degradation of function.



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5.2.3 Electrostatic Di	scharges	
RESULT:		Pass
Date of testing:	10-Nov-2016	
Ambient temperature: Relative humidity: Atmospheric pressure:	25°C 46% 91kPa	
Test procedure:	IEC 61000-4-2:200	08
Severity level: Number of discharges per Supply voltage during testi Test mode applied:	•	
Performance criterion:	В	
Met criterion:	В	

**Note:** The EUT was placed on a non-conductive support 80cm above a ground reference plane (GRP). The EUT and its attached cables were isolated from the GRP by a thin insulating support of 0.5mm thickness. Electrostatic discharges were applied using an ESD gun directly (via contact or air discharges). The EUT operation was monitored during the test.



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#### Table 10: Immunity against Electrostatic Discharges, both Polarities

Discharge Points	Type of Discharge	Test Voltages	Result	Remark		
Front Enclosure:						
	Contact	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
	VCP	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
	HCP	±2, ±4kV	Pass	During test at ±2kV display went to sleep mode & recovered back after the test.		
	Air	±2, ±4, ±8kV	Pass	EUT operated as intended, no degradation of function.		
Left Enclosure:						
	Contact	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
	VCP, HCP	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
Right Enclosure	e:					
	Contact	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
	VCP, HCP	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
Rear Enclosure	:		•	·		
	Contact	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
	VCP, HCP	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
Top Enclosure						
	Contact	±2, ±4kV	Pass	EUT operated as intended, no degradation of function.		
Cables:						
	Air	±2, ±4, ±8kV	Pass	EUT operated as intended, no degradation of function.		
Display:						
	Air	±2, ±4, ±8kV	Pass	During test at -4kV, ±8kV display went to sleep mode & recovered back after the test.		





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5.3 Power Supply	y Alterations	
5.3.1 Voltage Dips		
RESULT:		Pass
Date of testing:	08-Nov-2016	
Ambient temperature: Relative humidity: Atmospheric pressure:	26°C 55% 91kPa	
Test procedure:	IEC 61000-4-11	1:2004
Test parameters: Starting phases: Number of voltage dips: Time between voltage dip Supply voltage during tes	Performance cr Met criterion:A -100%, 1 cycle, Performance cr Met criterion:A -60%, 12 cycles Performance cr Met criterion:B -30%, 30 cycles Performance cr Met criterion:B -20%, 300cycle Performance cr Met criterion:B 0° 3 (for each para 60s	16.7ms @ 60Hz iterion: B s, 200ms @ 60Hz iterion: B s, 500ms @ 60Hz iterion: B s, 5000ms @ 60Hz
Test mode applied:	А	
Note:		
	to a test generator. The specified	

The EUT was connected to a test generator. The specified series of voltage dips were applied in sequence at the AC mains input port of the EUT. The EUT operation was monitored during the test.



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### Table 11: Immunity against Voltage Dips, AC 120V, 60Hz Input Voltage

Voltage Reduction	Applied Voltage	Duration	Starting Phase [rad]	Result	Remark
100%	0V	8.3ms	0	Pass	EUT operated as intended, no degradation of function.
100%	0V	16.7ms	0	Pass	EUT operated as intended, no degradation of function.
60%	48V	200ms	0	Pass	EUT changed to Battery mode & recovered back.
30%	84V	500ms	0	Pass	EUT changed to Battery mode & recovered back
20%	96V	5000ms	0	Pass	EUT changed to Battery mode & recovered back





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5.3.2 Voltage Interruptions	
RESULT: P	ASS
Date of testing: 08-Nov-2016	
Ambient temperature:26°CRelative humidity:55%Atmospheric pressure:91kPa	
Test procedure: IEC 61000-4-11:2004	
Test parameters:-100%, 300 cycles, 5000ms @ 60HzStarting phases:0°Number of voltage interruptions:3 (for each parameter combination)Time between voltage interruptions:60sSupply voltage during testing:120V ACTest mode applied:A	
Performance criterion: B	
Met criterion: B	

#### Note:

The EUT was connected to a test generator. The specified series of voltage interruptions was applied at the AC mains input port of the EUT. The EUT operation was monitored during the test.

#### Table 12: Immunity against Voltage Interruptions, AC 120V, 60Hz Input Voltage

Voltage Reduction	Applied Voltage	Duration	Starting Phase [rad]	Result	Remark
100%	0V	5s	0	Pass	EUT changed to Battery mode & recovered back



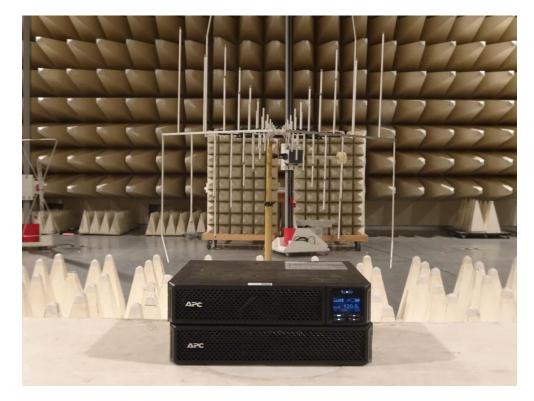
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6. Photographs of the Test Set-Up

Photograph 1: Set-up for Radiated Susceptibility, Vertical Polarization







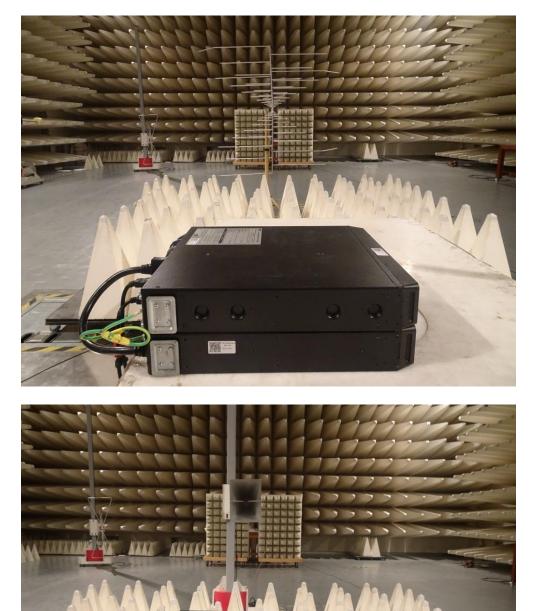
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Photograph 2: Set-up for Radiated Susceptibility, Horizontal Polarization





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Photograph 3: Set-up for Conducted Susceptibility, CDN Injection Method, AC Input and Output Power Port



Photograph 4: Set-up for Conducted Susceptibility, EM clamp Method, Signal Port



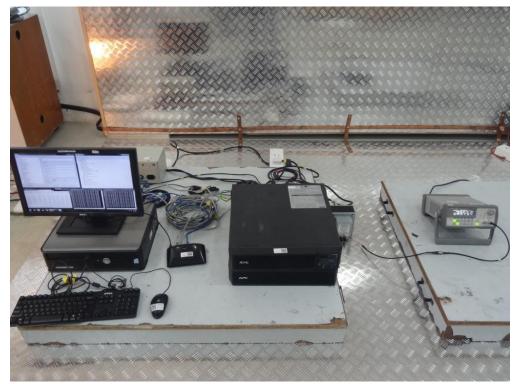


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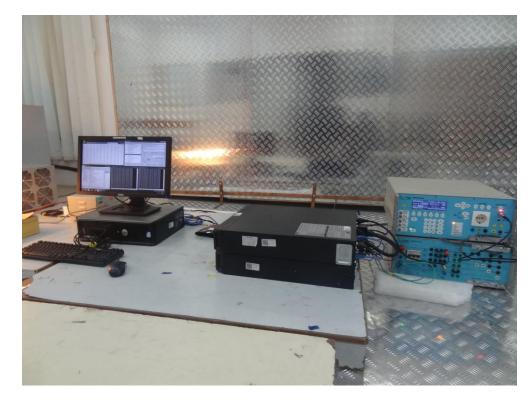
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Photograph 5: Set-up for Low Frequency Conducted Immunity



Photograph 6: Set-up for Electrical Fast Transients and Bursts, on AC Input and Output Power Ports



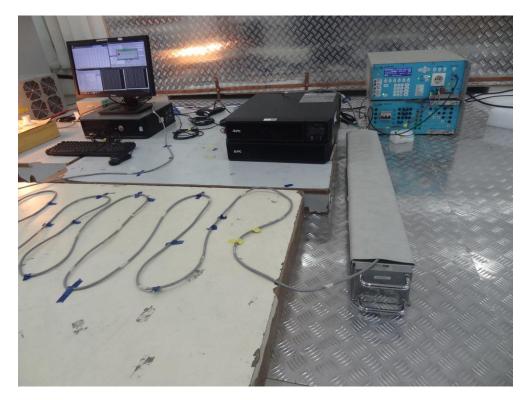


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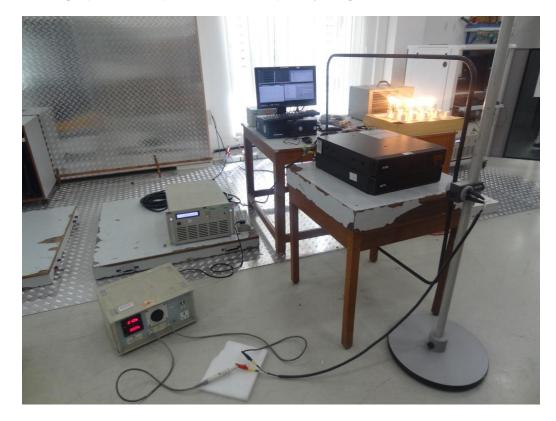
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Photograph 7: Set-up for Electrical Fast Transients and Bursts, on Signal Ports



Photograph 8: Set-up for Power Frequency Magnetic Field



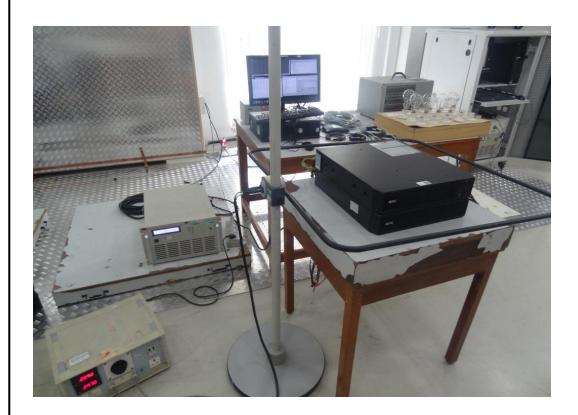


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Photograph 9: Set-up for Surges, on AC Input and Output Power Ports







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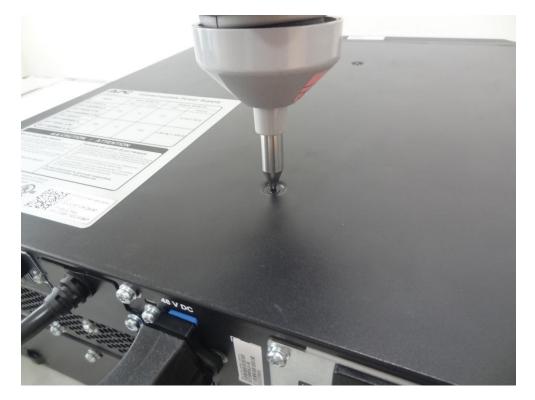
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Photograph 10: Set-up for Surges, on Signal Ports



Photograph 11: Set-up for Electrostatic Discharges, Contact Discharges





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Photograph 12: Set-up for Electrostatic Discharges, Air Discharges



Photograph 13: Set-up for Electrostatic Discharges, VCP





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Photograph 14: Set-up for Electrostatic Discharges, HCP



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